

Title (en)
SECOND SCHOTTKY CONTACT METAL LAYER TO IMPROVE GaN SCHOTTKY DIODE PERFORMANCE

Title (de)
ZWEITE SCHOTTKY-KONTAKT-METALLSCHICHT ZUR ERHÖHUNG DER LEISTUNG EINER GAN-SCHOTTKY-DIODE

Title (fr)
SECONDE COUCHE DE METAL SUR CONTACT SCHOTTKY DESTINEE A AMELIORER LES PERFORMANCES D UNE DIODE SCHOTTKY AU
GaN

Publication
EP 1949445 A4 20090819 (EN)

Application
EP 06837446 A 20061113

Priority
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• US 58912406 A 20061027

Abstract (en)
[origin: US2007108547A1] A Schottky contact is disposed atop a surface of a semiconductor. A first Schottky contact metal layer is disposed atop a first portion of the semiconductor surface. A second Schottky contact metal is disposed atop a second portion of the surface layer and adjoins the first Schottky contact metal layer. The first Schottky contact metal layer has a lower work function than the second Schottky contact metal layer.

IPC 8 full level
H01L 29/47 (2006.01)

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H01L 21/28581 (2013.01 - EP US); **H01L 29/47** (2013.01 - EP US); **H01L 29/475** (2013.01 - EP US); **H01L 29/66143** (2013.01 - EP US);
H01L 29/7786 (2013.01 - US); **H01L 29/7787** (2013.01 - EP US); **H01L 29/872** (2013.01 - EP US); **H01L 29/2003** (2013.01 - EP US)

Citation (search report)
• [X] US 2003098462 A1 20030529 - YOSHIDA SEIKOH [JP]
• [X] JP 2005317843 A 20051110 - FURUKAWA ELECTRIC CO LTD
• [X] JP 2004186558 A 20040702 - FURUKAWA ELECTRIC CO LTD
• [PX] EP 1643561 A2 20060405 - FURUKAWA ELECTRIC CO LTD [JP]
• [X] YOSHIDA S ET AL: "A new GaN based field effect schottky barrier diode with a very low on-voltage operation", POWER SEMICONDUCTOR DEVICES AND ICS, 2004. PROCEEDINGS. ISPSD '04. THE 16TH INTERNATIONAL SYMPOSIUM ON KITAKYUSHU INT. CONF. CTR, JAPAN MAY 24-27, 2004, PISCATAWAY, NJ, USA, IEEE, 24 May 2004 (2004-05-24), pages 323 - 326, XP010723404, ISBN: 978-4-88686-060-6
• See references of WO 2007059035A2

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EP 2416364 A3 20120711; EP 2421045 A1 20120222; JP 2009516391 A 20090416; JP 2013153185 A 20130808; JP 5390188 B2 20140115;
US 2012043551 A1 20120223; US 2014110721 A1 20140424; US 8629525 B2 20140114; US 8823013 B2 20140902;
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JP 2013048906 A 20130312; US 2006043992 W 20061113; US 201113200206 A 20110921; US 201314105057 A 20131212